

MAY 2015

# **FQB1P50**

# P-Channel QFET® MOSFET

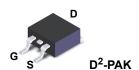
- 500 V, - 1.5 A, 10.5  $\Omega$ 

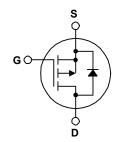
### **Description**

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

### **Features**

- - 1.5 A, 500 V,  $R_{DS(on)}$  = 10.5  $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_{D}$  = 0.75 A
- Low Gate Charge (Typ. 11 nC)
- Low Crss (Typ. 6.0 pF)
- 100% Avalanche Tested
- RoHS Compliant





## **Absolute Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQB1P50TM	Unit
V <sub>DSS</sub>	Drain-Source Voltage		-500	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		-1.5	Α
	- Continuous (T <sub>C</sub> = 100°C	C)	-0.95	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-6.0	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	110	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-1.5	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	6.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		3.13	W
	Power Dissipation (T <sub>C</sub> = 25°C)		63	W
	- Derate above 25°C		0.51	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	Э	-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	FQB1P50TM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	1.98	
Ъ	Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max.	62.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (1 in <sup>2</sup> pad of 2 oz copper), Max.	40	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB1P50	FQB1P50TM	D2-PAK	330mm	24mm	800

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T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-500			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, Referenced to 25°C		-		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -500 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -400 \text{ V}, T_C = 125 ^{\circ}\text{C}$			-1 -10	μA μA
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

## On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -0.75 A		8.0	10.5	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -50 \text{ V}, I_{D} = -0.75 \text{ A}$		1.26		S

## **Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$	 270	350	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz	 40	50	pF
$C_{rss}$	Reverse Transfer Capacitance		 6.0	8.0	pF

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -250 V, I <sub>D</sub> = -1.5 A,	 9.0	30	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$	 25	60	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1.G - 20 11	 27	65	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	 30	70	ns
$Q_g$	Total Gate Charge	V <sub>DS</sub> = -400 V, I <sub>D</sub> = -1.5 A,	 11	14	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = -10 V	 2.0		nC
$Q_{qd}$	Gate-Drain Charge	(Note 4)	 5.6		nC

Drain-Source Diode Characteristics and Maximum Ratings

Diaiii	Diani-Source Diode Onaracteristics and Maximum Nathigs						
IS	Maximum Continuous Drain-Source Diode Forward Current				-1.5	Α	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				-6.0	Α	
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.5 \text{ A}$			-5.0	V	
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = -1.5 \text{ A,}$		200		ns	
$Q_{rr}$	Reverse Recovery Charge	$dI_{F} / dt = 100 A/\mu s$		0.7		μC	

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 88mH,  $I_{AS}$  = -1.5A,  $V_{DD}$  = -50V,  $R_G$  = 25  $\Omega$ , Starting  $T_J$  = 25°C 3.  $I_{SD}$  ≤ -1.5A, di/dt ≤ 200A/ $\mu$ s,  $V_{DD}$  ≤ BV $_{DSS}$ , Starting  $T_J$  = 25°C

- 4. Essentially independent of operating temperature

## **Typical Characteristics**

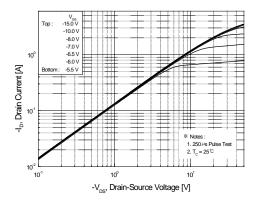


Figure 1. On-Region Characteristics

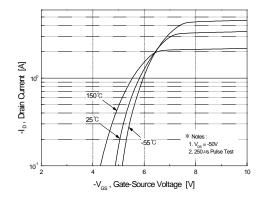


Figure 2. Transfer Characteristics

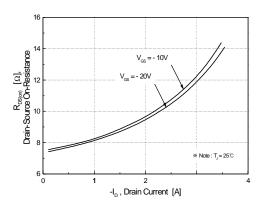


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

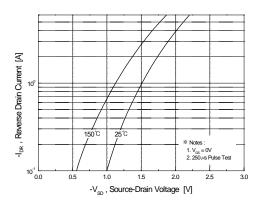


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

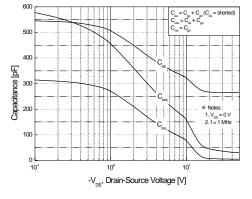


Figure 5. Capacitance Characteristics

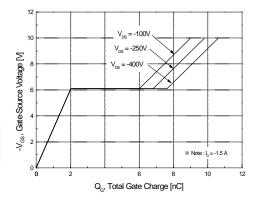


Figure 6. Gate Charge Characteristics

## Typical Characteristics (Continued)

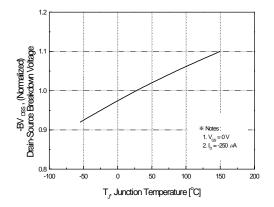
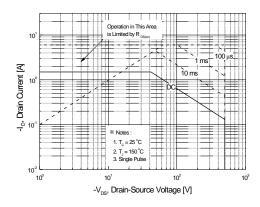


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



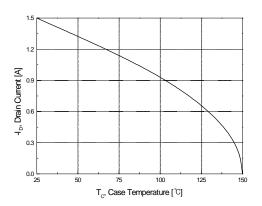


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

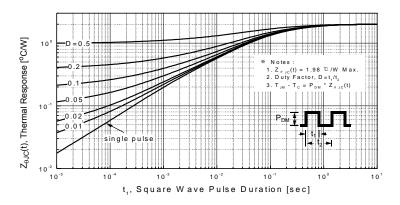


Figure 11. Transient Thermal Response Curve



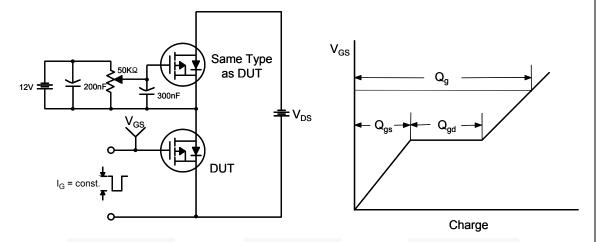


Figure 13. Resistive Switching Test Circuit & Waveforms

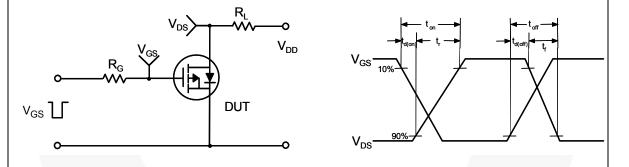


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

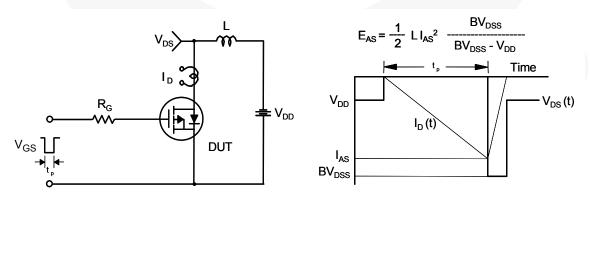
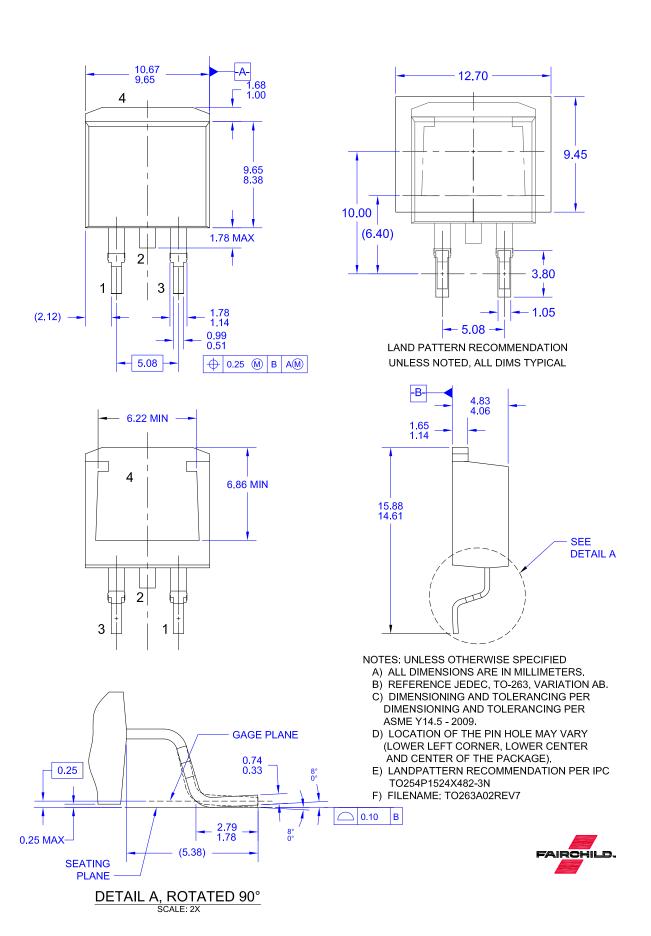


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms DUT I<sub>SD</sub> Driver Compliment of DUT 
 Image: Section of the property (N-Channel)  $\prod V_{GS}$ • dv/dt controlled by R<sub>G</sub> • I<sub>SD</sub> controlled by pulse period Gate Pulse Width  $V_{GS}$ Gate Pulse Period 10V (Driver) **Body Diode Reverse Current** I<sub>SD</sub> (DUT) di/dt  $I_{\text{FM}}$  , Body Diode Forward Current V<sub>DS</sub>  $V_{\text{SD}}$ (DUT) Body Diode Forward Voltage Drop Body Diode Recovery dv/dt







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Definition of Terms					
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